## Applicant(s)/Patent Under Application/Control No. Reexamination 10/026,242 ZEHETNER, JOHANN Notice of References Cited Art Unit Examiner Page 1 of 1 1764 Hien Tran **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 428/116 05-1989 Cyron, Theodor US-4,832,998 422/180 04-1994 Tanaka et al. US-5,304,351 В 422/180 08-1998 Humpolik et al. US-5,797,183 C 422/180 US-6,458,329 10-2002 Wieres, Ludwig D Ε US-F US-US-G Н US-US-1 J US-K US-US-US-М **FOREIGN PATENT DOCUMENTS** Date Document Number Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.